

<b>Notice of References Cited</b>	Application/Control No. 10/600,014	Applicant(s)/Patent Under Reexamination CHATTERJEE ET AL.	
	Examiner Shew-Fen Lin	Art Unit 2166	Page 1 of 1

**U.S. PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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	U	Electrical Schematics Page, April 25, 2002, <a href="http://www.jlab.org/accel/inj_group/elec1.htm">http://www.jlab.org/accel/inj_group/elec1.htm</a>
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